

ESREF 2018: Schedule at a glance

Monday, October 1						Tuesday, October 2					Wednesday, October 3					Thursday, October 4					Friday, October 5							
Room A Hall East	Room B Musik- salen	Room C Laug- stuen	Room D Latiner- stuen	Exhibition area		Room A Hall East	Room B Musik- salen	Room C Laug- stuen	Room D Latiner- stuen	Exhibition area		Room A Hall East	Room B Musik- salen	Room C Laug- stuen	Room D Latiner- stuen	Exhibition area		Room A Hall East	Room B Musik- salen	Room C Laug- stuen	Room D Latiner- stuen	Exhibition area						
08:00																												
08:20																												
08:40																												
09:00		TUTORIAL 1 Reliability Issues in power SiC and GaN			Exhibition set up	E1-2	A-1	K-2	IND1	Exhibition		E2-3	L-1	SS1-1		Exhibition		C-2	I-1	G	ECPE Workshop W3	Exhibition						
09:20																												
09:40																												
10:00																												
10:20					Coffee break																							
10:40																												
11:00		TUTORIAL 3 Reliability of packages for power devices	TUTORIAL 2 Dielectric reliability in micro- electronics		Exhibition set up	B. Linder						F. Altmann	M.B. Tahoori															
11:20						E1-3	A-2	BP IPFA B1-1	IND2	Exhibition		F-2	L-2	SS1-2	Workshop W1	Exhibition		C-3	I-2	D	Workshop W4	Exhibition						
11:40																												
12:00																												
12:20																												
12:40					Lunch					Lunch																		
13:00																												
13:20																												
13:40		TUTORIAL 5 Introduction to the modern reliability	TUTORIAL 4 Moisture Modeling in Complex Systems			J. Lutz	N. Stojadi- novic					R. Ambat	P. Pfäffli															
14:00					Exhibition set up	E2-1	A-3	BP IRPS	IND3	Exhibition		F-3	L-3	SS1-3	Workshop W2	Exhibition												
14:20																												
14:40																												
15:00	Opening session																											
15:20	P. Gargini																											
15:40																												
16:00	P.C. Kjær																											
16:20																												
16:40					Coffee break	E2-2	H	B3																				
17:00		E1-1	F-1	C-1	K-1																							
17:20																												
17:40																												
18:00																												
18:20																												
18:40																												
19:00					Aalborg City buffet																							
19:20																												
19:40																												
20:00																												
20:20																												
20:40																												
22:00																												

Tracks

- A - Quality and Reliability Assessment Techniques and Methods for Devices and Systems
- B1 - Si-Technologies & Nanoelectronics: Hot Carriers, High-K, Gate Materials
- B2 - Si-Technologies & Nanoelectronics: Low-K, Cu Interconnects
- B3 - Si-Technologies & Nanoelectronics: ESD, EMI and Latch-up
- C - Progress in Failure Analysis: Defect Detection and Analysis
- D - Reliability of Microwave and Compound Semiconductors Devices
- E1 - Power Devices Reliability - Silicon and Passive

- F - Packaging and Assembly Reliability
- G - MEMS, Sensors and Organic Electronics Reliability
- H - Photonics Reliability
- I - Extreme Environments and Radiation
- K - Renewable Energies Reliability
- L - Modeling for Reliability
- SS1- Reliability in Traction Applications